

Application/Control No.	Applicant(s)/Patent under Reexamination	•
10/635,468	OSHIMA ET AL.	
Examiner	Art Unit	•
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Cla	ıss	Subclass	Date	Examiner
37	' 5	261,271,	12/19/2005	DH
		279,281		
		298,308,		
		329,332		
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INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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